Special Issue

Photonic Technology for Precision Metrology

Message from the Guest Editor

This issue focuses on metrology principles and measurement instrumentation in optical technology to solve challenging engineering problems.

Technical topics include (but are not limited):

- optical imaging and reflectometry;
- interferometry and spectroscopy;
- radiometry and photometry;
- remote and in-situ sensing;
- optoelectronic sensors and smart-sensors;
- optical sensors for robots and unmanned systems;
- industrial optical measurements;
- high resolution optical metrology;
- fiber-optic measurements;
- optical frequency metrology and optical clocks;
- optical sources and detectors;
- photonic metrological technology for science, environment, medicine, security, telecommunication, and space.

Guest Editor

Dr. Jacek Wojtas
Institute of Optoelectronics, Military University of Technology, gen. Sylwestra Kaliskiego 2 Str., 00-908 Warsaw, Poland

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Deadline for manuscript submissions

closed (20 January 2022)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/40180

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

mdpi.com/journal/applsci